





参考資料



CD54HC4024, CD74HC4024 CD54HCT4024, CD74HCT4024

JAJSO98D - NOVEMBER 1997 - REVISED MARCH 2022

CDx4HC4024、CDx4HCT4024 ハイスピード CMOS ロジック、7 段バイナリ・リ ップルカウンタ

1 特長

- 完全静的動作
- バッファ付き入力
- コモン・リセット
- ネガティブ・エッジ・クロッキング
- ファンアウト(全温度範囲にわたって)
 - 標準出力:10 の LSTTL 負荷
 - バス・ドライバ出力:15 の LSTTL 負荷
- 広い動作温度範囲:-55℃~125℃
- 平衡な伝搬遅延と遷移時間
- LSTTL ロジック IC に比べて消費電力を大幅削減
- HC タイプ
 - 2V~6V で動作
 - 優れたノイズ耐性: $N_{IL} = V_{CC}$ の 30%、 $N_{IH} = V_{CC}$ の 30% (VCC = 5V の場合)
- HCT タイプ
 - 4.5V~5.5V で動作
 - LSTTL 入力ロジックと直接互換、 V_{IL} = 0.8V (最大値)、V_{IH} = 2V (最小値)
 - CMOS 入力互換、V_{OL}、V_{OH} で I_I ≤ 1µA

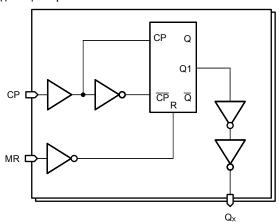
2 概要

HC4024 および HCT4024 は、7 段リップルキャリー・バイ ナリ・カウンタです。すべてのカウンタ段は、フリップ・フロッ プです。段の状態は、各入力パルスの負の遷移時に1カ ウント進み、MR ラインが High レベルになると、すべての カウンタがゼロ状態にリセットされます。すべての入出力は バッファ付きです。

デバイス情報

Z Y Y Y Y Y Y Y Y Y Y Y Y Y Y Y Y Y Y Y												
部品番号	パッケージ(1)	本体サイズ (公称)										
CD74HC4024M	SOIC (14)	8.65mm × 3.90mm										
CD74HCT4024M	SOIC (14)	8.65mm × 3.90mm										
CD74HC4024E	PDIP (14)	19.31mm × 6.35mm										
CD74HCT4024E	PDIP (14)	19.31mm × 6.35mm										
CD74HC4024PW	TSSOP (14)	5.00mm × 4.40mm										
CD54HC4024F	CDIP (14)	19.55mm × 6.71mm										

(1) 利用可能なすべてのパッケージについては、このデータシートの 末尾にある注文情報を参照してください。



機能ブロック図



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3 Revision History

資料番号末尾の英字は改訂を表しています。その改訂履歴は英語版に準じています。

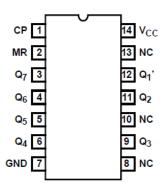
Changes from Revision C (October 2003) to Revision D (March 2022) 最新のデータシート規格を反映するように、文書全体の採番、書式設定、表、図、相互参照を更新......1

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4 Pin Configuration and Functions



J, N, D or PW Package 14-Pin CDIP, PDIP, SOIC, or TSSOP Top View



5 Specifications

5.1 Absolute Maximum Ratings⁽¹⁾

			MIN	MAX	UNIT
V _{CC}	Supply voltage		- 0.5	7	V
I _{IK}	Input diode current	For $V_1 < -0.5 \text{ V}$ or $V_1 > V_{CC} + 0.5 \text{ V}$		±20	mA
I _{OK}	Output diode current	For $V_O < -0.5 \text{ V}$ or $V_O > V_{CC} + 0.5 \text{ V}$		±20	mA
Io	Output source or sink current per output pin	$ForV_O > -0.5 V or V_O < V_{CC} + 0.5 V$		±25	mA
	Continuous current through V _{CC} or GND			±50	mA
TJ	Junction temperature			150	°C
T _{stg}	Storage temperature range		– 65	150	°C
	Lead temperature (soldering 10s) (SOIC - lead to	ips only)		300	°C

⁽¹⁾ Stresses beyond those listed under *absolute maximum ratings* may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these or any other conditions beyond those indicated under *recommended operating conditions* is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

5.2 Recommended Operating Conditions

			MIN	MAX	UNIT
V	Cupply voltage range	HC Types	2	6	V
	Supply voltage range	HCT Types	4.5	5.5	V
V _I , V _O	DC input or output voltage		0	V _{CC}	V
t _t		2 V		1000	
	Input rise and fall time	4.5 V		500	ns
		6 V		400	
T _A	Temperature range	'	– 55	125	°C

5.3 Thermal Information

		D (SOIC)	N (PDIP)	PW (TSSOP)	
THERM	AL METRIC	14 PINS	14 PINS	14 PINS	UNIT
$R_{\theta JA}$	Junction-to-ambient thermal resistance ⁽¹⁾	86	80	113	°C/W

⁽¹⁾ For more information about traditional and new thermal metrics, see the Semiconductor and IC package thermal metrics application report.



5.4 Electrical Characteristics

	PARAMETER	TEST	Vcc		25℃		–40℃ to	85℃	–55℃ to	UNIT		
	PAKAWETEK	CONDITIONS(2)	(V)	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNII	
HC T	(PES					'				'		
			2	1.5			1.5		1.5			
V_{IH}	High level input voltage		4.5	3.15			3.15		3.15		V	
			6	4.2			4.2		4.2			
			2			0.5		0.5		0.5		
V_{IL}	Low level input voltage		4.5			1.35		1.35		1.35	V	
			6			1.8		1.8		1.8		
	High level output	I _{OH} = – 20 μA	2	1.9			1.9		1.9			
	voltage	I _{OH} = – 20 μA	4.5	4.4			4.4		4.4			
.,	CMOS loads	I _{OH} = – 20 μA	6	5.9			5.9		5.9		V	
V _{OH}	High level output	I _{OH} = – 4 mA	4.5	3.98			3.84		3.7		V	
	voltage TTL loads	I _{OH} = – 5.2 mA	6	5.48			5.34		5.2			
	Low level output	I _{OL} = 20 μA	2			0.1		0.1		0.1		
	voltage	I _{OL} = 20 μA	4.5			0.1		0.1		0.1		
V _{OL}	CMOS loads	I _{OL} = 20 μA	6			0.1		0.1		0.1		
	Low level output	I _{OL} = 4 mA	4.5			0.26		0.33		0.4	V	
	voltage TTL loads	I _{OL} = 5.2 mA	6			0.26		0.33		0.4		
l _l	Input leakage current	V _{CC} or GND	6			±0.1		±1		±1	μΑ	
I _{CC}	Quiescent device current	V _{CC} or GND	6			8		80		160	μA	
HCT 1	YPES						,					
V _{IH}	High level input voltage		4.5 to 5.5	2			2		2		V	
V _{IL}	Low level input voltage		4.5 to 5.5			0.8		0.8		0.8	V	
./	High level output voltage CMOS loads	I _{OH} = – 20 μA	4.5	4.4			4.4		4.4		V	
V _{OH}	High level output voltage TTL loads	I _{OH} = – 4 mA	4.5	3.98			3.84		3.7		V	
M	Low level output voltage	Ι _{ΟL} = 20 μΑ	4.5			0.1		0.1		0.1	V	
V _{OL}	Low level output voltage	I _{OL} = 4 mA	4.5			0.26		0.33		0.4	v	
I	Input leakage current	V _{CC} and GND	5.5			±0.1		±1		±1	μΑ	
СС	Supply current	V _{CC} or GND	5.5			8		80		160	μΑ	
ΔI _{CC}	Additional supply current per input pin	CP, MR inputs held at V _{CC} - 2.1	4.5 to 5.5		100	180		225		245	μΑ	

⁽¹⁾ For dual-supply systems theoretical worst case (V_I = 2.4 V, V_{CC} = 5.5 V) specification is 1.8 mA. (2) V_I = V_{IH} or V_{IL} , unless otherwise noted.



5.5 Prerequisite for Switching Specifications

	DADAMETED	V 00	25℃	;	-40℃ to 8	5°C	-55℃ to 12	:5℃	LINUT
	PARAMETER	V _{CC} (V)	MIN	MAX	MIN	MAX	MIN	MAX	UNIT
нс т	YPES								
		2	6		5		4		MHz
f_{MAX}	Maximum input pulse frequency	4.5	30		24		20		MHz
		6	35		29		24		MHz
		2	80		100		120		ns
t _W	Input pulse width	4.5	16		20		24		ns
		6	14		17		20		ns
		2	50		65		75		ns
t_{REM}	Reset removal time	4.5	10		13		15		ns
		6	9		11		13		ns
		2	80		100		120		ns
t _W	Reset pulse width	4.5	16		20		24		ns
		6	14		17		20		ns
нст	TYPES	'		'		'			
f_{MAX}	Maximum input pulse frequency	4.5	25		20		16		MHz
t _W	Input pulse width	4.5	20		25		30		ns
t _{REC}	Reset recovery time	4.5	10		13		15		ns
t _W	Reset pulse width	4.5	20		25		30		ns



5.6 Switching Characteristics

t_r, t_f = 6 ns. See (Parameter Measurement Information)

	PARAMETER	TEST CONDITIONS	V _{CC} (V)		25℃		-40°0 85°		-55℃ to 125℃	UNIT
		CONDITIONS		MIN	TYP	MAX	MIN	MAX	MIN MAX	
HC TYPE	S									
		C _L = 50 pF	2			140		175	210	ns
	Propagation delay time	CL = 50 pr	4.5			28		35	42	ns
t _{PLH} , t _{PHL}	CP to Q1' output	C _L = 15 pF	5		11					ns
		C _L = 50 pF	6			24		30	36	ns
		C _L = 50 pF	2			75		95	110	ns
	Propagation delay time,	C _L = 50 pr	4.5			15		19	22	ns
t _{PLH} , t _{PHL}	Q_n to $Q_n + 1$	C _L = 15 pF	5		6					ns
		C _L = 50 pF	6			13		13	19	ns
			2			170		215	255	ns
	Propagation delay time,	C _L = 50 pF	4.5			34		43	51	ns
t _{PLH} , t _{PHL}	MR to Q _n	CL = 50 pr	5		14					ns
			6			29		27	43	ns
			2			75		95	110	ns
t _{TLH} , t _{THL}	Output transition time	C _L = 50 pF	4.5			15		19	22	ns
			6			13		16	19	ns
C _{IN}	Input capacitance	C _L = 50 pF				10		10	10	pF
C _{PD}	Power dissipation capacitance ⁽¹⁾ (2)	C _L = 15 pF	5		30					pF
HCT TYP	ES									1
		0 50 5	4.5			40			00	ns
	Propagation delay time	$C_L = 50 pF$	4.5			40		50	60	ns
t _{PLH} , t _{PHL}	CP to Q1' output	0 45 5	_		47					ns
		$C_L = 15 pF$	5		17					ns
	Propagation delay time,	C _L = 50 pF	4.5			15		19	22	ns
t _{PLH} , t _{PHL}	Q_n to $Q_n + 1$	C _L = 15 pF	5		6					ns
	Propagation delay time,	C _L = 50 pF	4.5			40		50	60	
t _{PLH} , t _{PHL}	MR to Q _n	C _L = 15 pF	5		17					
t _{TLH} , t _{THL}	Output transition time	C _L = 50 pF	4.5			15		19	22	ns
C _{IN}	Input capacitance	C _L = 15 pF				10		10	10	pF
C _{PD}	Power dissipation capacitance ⁽¹⁾ (2)	C _L = 15 pF	5		30					pF

 C_{PD} is used to determine the dynamic power consumption, per buffer. $P_D = V_{CC}^2 f_i + \Sigma (C_L V_{CC}^2 f_i/M)$ where: $M = 2^1, 2^2, 2^3, 2^4, 2^5, 2^6, 2^7 f_i$ = input frequency, C_L = output load capacitance, V_{CC} = supply

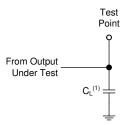


6 Parameter Measurement Information

Phase relationships between waveforms were chosen arbitrarily. All input pulses are supplied by generators having the following characteristics: PRR \leq 1 MHz, $Z_O = 50 \Omega$, $t_t < 6 \text{ ns}$.

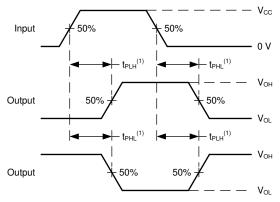
For clock inputs, f_{max} is measured when the input duty cycle is 50%.

The outputs are measured one at a time with one input transition per measurement.



(1) C_L includes probe and test-fixture capacitance.

図 6-1. Load Circuit for Push-Pull Outputs



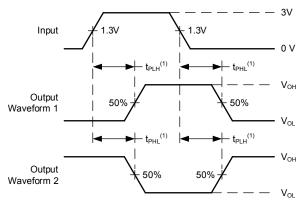


Input 00%

(1) The greater between t_r and t_f is the same as t_t.

図 6-3. Voltage Waveforms, Input and Output Transition Times for Standard CMOS Inputs





(1) The greater between t_{PLH} and t_{PHL} is the same as t_{pd} .

図 6-4. Voltage Waveforms, Propagation Delays for TTL-Compatible Inputs

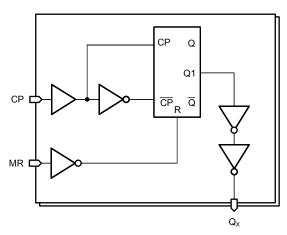


7 Detailed Description

7.1 Overview

The 'HC4024 and 'HCT4024 are 7-stage ripple-carry binary counters. All counter stages are flip-flops. The state of the stage advances one count on the negative transition of each input pulse; a high voltage level on the MR line resets all counters to their zero state. All inputs and outputs are buffered.

7.2 Functional Block Diagram



7.3 Device Functional Modes

表 7-1. Truth Table⁽¹⁾

CP COUNT	MR	OUTPUT STATE
<u> </u>	L	No change
\	L	Advance to next state
X	Н	All outputs are low

(1) H = high voltage level, L = low voltage level, X = don't care, \uparrow = transition from low to high level, \downarrow = transition from high to low.



8 Power Supply Recommendations

The power supply can be any voltage between the minimum and maximum supply voltage rating located in the *Recommended Operating Conditions*. Each V_{CC} terminal should have a good bypass capacitor to prevent power disturbance. A 0.1- μ F capacitor is recommended for this device. It is acceptable to parallel multiple bypass caps to reject different frequencies of noise. The 0.1- μ F and 1- μ F capacitors are commonly used in parallel. The bypass capacitor should be installed as close to the power terminal as possible for best results.

9 Layout

9.1 Layout Guidelines

When using multiple-input and multiple-channel logic devices inputs must not ever be left floating. In many cases, functions or parts of functions of digital logic devices are unused; for example, when only two inputs of a triple-input AND gate are used or only 3 of the 4 buffer gates are used. Such unused input pins must not be left unconnected because the undefined voltages at the outside connections result in undefined operational states. All unused inputs of digital logic devices must be connected to a logic high or logic low voltage, as defined by the input voltage specifications, to prevent them from floating. The logic level that must be applied to any particular unused input depends on the function of the device. Generally, the inputs are tied to GND or V_{CC} , whichever makes more sense for the logic function or is more convenient.



10 Device and Documentation Support

TI offers an extensive line of development tools. Tools and software to evaluate the performance of the device, generate code, and develop solutions are listed below.

10.1 Receiving Notification of Documentation Updates

To receive notification of documentation updates, navigate to the device product folder on ti.com. Click on *Subscribe to updates* to register and receive a weekly digest of any product information that has changed. For change details, review the revision history included in any revised document.

10.2 サポート・リソース

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10.3 Trademarks

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10.4 Electrostatic Discharge Caution



This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

10.5 Glossary

TI Glossary

This glossary lists and explains terms, acronyms, and definitions.

11 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.



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PACKAGING INFORMATION

Orderable Device	Status (1)	Package Type	Package Drawing	Pins	Package Qty	Eco Plan	Lead finish/ Ball material	MSL Peak Temp	Op Temp (°C)	Device Marking (4/5)	Samples
CD54HC4024F	ACTIVE	CDIP	J	14	25	Non-RoHS & Green	SNPB	N / A for Pkg Type	-55 to 125	CD54HC4024F	Samples
CD54HCT4024F3A	ACTIVE	CDIP	J	14	25	Non-RoHS & Green	SNPB	N / A for Pkg Type	-55 to 125	CD54HCT4024F3A	Samples
CD74HC4024E	ACTIVE	PDIP	N	14	25	RoHS & Green	NIPDAU	N / A for Pkg Type	-55 to 125	CD74HC4024E	Samples
CD74HC4024M96	ACTIVE	SOIC	D	14	2500	RoHS & Green	NIPDAU SN	Level-1-260C-UNLIM	-55 to 125	HC4024M	Samples
CD74HC4024PWR	ACTIVE	TSSOP	PW	14	2000	RoHS & Green	NIPDAU SN	Level-1-260C-UNLIM	-55 to 125	HJ4024	Samples
CD74HCT4024E	ACTIVE	PDIP	N	14	25	RoHS & Non-Green	NIPDAU	N / A for Pkg Type	-55 to 125	CD74HCT4024E	Samples
CD74HCT4024EE4	ACTIVE	PDIP	N	14	25	RoHS & Non-Green	NIPDAU	N / A for Pkg Type	-55 to 125	CD74HCT4024E	Samples
CD74HCT4024M	ACTIVE	SOIC	D	14	50	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-55 to 125	HCT4024M	Samples

(1) The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

(2) RoHS: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (CI) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

⁽³⁾ MSL, Peak Temp. - The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

⁽⁴⁾ There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.

PACKAGE OPTION ADDENDUM

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(5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.

(6) Lead finish/Ball material - Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

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In no event shall TI's liability arising out of such information exceed the total purchase price of the TI part(s) at issue in this document sold by TI to Customer on an annual basis.

OTHER QUALIFIED VERSIONS OF CD54HC4024, CD54HCT4024, CD74HC4024, CD74HCT4024:

Catalog: CD74HC4024, CD74HCT4024

Military: CD54HC4024, CD54HCT4024

NOTE: Qualified Version Definitions:

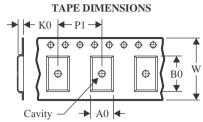
- Catalog TI's standard catalog product
- Military QML certified for Military and Defense Applications

PACKAGE MATERIALS INFORMATION

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TAPE AND REEL INFORMATION





A0	Dimension designed to accommodate the component width
В0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE

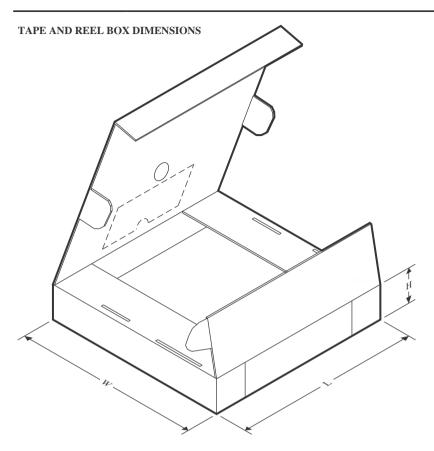


*All dimensions are nominal

Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
CD74HC4024M96	SOIC	D	14	2500	330.0	16.4	6.5	9.0	2.1	8.0	16.0	Q1
CD74HC4024M96	SOIC	D	14	2500	330.0	16.4	6.5	9.0	2.1	8.0	16.0	Q1
CD74HC4024PWR	TSSOP	PW	14	2000	330.0	12.4	6.9	5.6	1.6	8.0	12.0	Q1
CD74HC4024PWR	TSSOP	PW	14	2000	330.0	12.4	6.9	5.6	1.6	8.0	12.0	Q1
CD74HC4024PWR	TSSOP	PW	14	2000	330.0	12.4	6.85	5.45	1.6	8.0	12.0	Q1



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*All dimensions are nominal

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Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
CD74HC4024M96	SOIC	D	14	2500	356.0	356.0	35.0
CD74HC4024M96	SOIC	D	14	2500	356.0	356.0	35.0
CD74HC4024PWR	TSSOP	PW	14	2000	356.0	356.0	35.0
CD74HC4024PWR	TSSOP	PW	14	2000	356.0	356.0	35.0
CD74HC4024PWR	TSSOP	PW	14	2000	366.0	364.0	50.0

PACKAGE MATERIALS INFORMATION

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TUBE



*All dimensions are nominal

Device	Package Name	Package Type	Pins	SPQ	L (mm)	W (mm)	T (µm)	B (mm)
CD74HC4024E	N	PDIP	14	25	506	13.97	11230	4.32
CD74HC4024E	N	PDIP	14	25	506	13.97	11230	4.32
CD74HCT4024E	N	PDIP	14	25	506	13.97	11230	4.32
CD74HCT4024E	N	PDIP	14	25	506	13.97	11230	4.32
CD74HCT4024EE4	N	PDIP	14	25	506	13.97	11230	4.32
CD74HCT4024EE4	N	PDIP	14	25	506	13.97	11230	4.32
CD74HCT4024M	D	SOIC	14	50	506.6	8	3940	4.32

CERAMIC DUAL IN LINE PACKAGE



Images above are just a representation of the package family, actual package may vary. Refer to the product data sheet for package details.

4040083-5/G





CERAMIC DUAL IN LINE PACKAGE



- 1. All controlling linear dimensions are in inches. Dimensions in brackets are in millimeters. Any dimension in brackets or parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
- 2. This drawing is subject to change without notice.
- 3. This package is hermitically sealed with a ceramic lid using glass frit.
- His package is remitted by sealed with a ceramic its using glass mit.
 Index point is provided on cap for terminal identification only and on press ceramic glass frit seal only.
 Falls within MIL-STD-1835 and GDIP1-T14.



CERAMIC DUAL IN LINE PACKAGE



D (R-PDSO-G14)

PLASTIC SMALL OUTLINE



- A. All linear dimensions are in inches (millimeters).
- B. This drawing is subject to change without notice.
- Body length does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0.006 (0,15) each side.
- Body width does not include interlead flash. Interlead flash shall not exceed 0.017 (0,43) each side.
- E. Reference JEDEC MS-012 variation AB.



D (R-PDSO-G14)

PLASTIC SMALL OUTLINE



- A. All linear dimensions are in millimeters.
- B. This drawing is subject to change without notice.
- C. Publication IPC-7351 is recommended for alternate designs.
- D. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Refer to IPC-7525 for other stencil recommendations.
- E. Customers should contact their board fabrication site for solder mask tolerances between and around signal pads.



PW (R-PDSO-G14)

PLASTIC SMALL OUTLINE



- A. All linear dimensions are in millimeters. Dimensioning and tolerancing per ASME Y14.5M—1994.
- B. This drawing is subject to change without notice.
- Body length does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0,15 each side.
- Body width does not include interlead flash. Interlead flash shall not exceed 0,25 each side.
- E. Falls within JEDEC MO-153



PW (R-PDSO-G14)

PLASTIC SMALL OUTLINE



- A. All linear dimensions are in millimeters.
- B. This drawing is subject to change without notice.
- C. Publication IPC-7351 is recommended for alternate designs.
- D. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Refer to IPC-7525 for other stencil recommendations.
- E. Customers should contact their board fabrication site for solder mask tolerances between and around signal pads.



N (R-PDIP-T**)

PLASTIC DUAL-IN-LINE PACKAGE

16 PINS SHOWN



- A. All linear dimensions are in inches (millimeters).
- B. This drawing is subject to change without notice.
- Falls within JEDEC MS-001, except 18 and 20 pin minimum body length (Dim A).
- The 20 pin end lead shoulder width is a vendor option, either half or full width.



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